

PPXRD15

Hyderabad – India 19th August 2017

An internal standard for pharmaceuticals The Art of dealing with compromise

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PPXRD Website – <u>www.icdd.com/ppxrd</u>

ICDD Website - www.icdd.com

Why small traces?

(Early detection contaminants/degradation products/ crystalline seed/highly potent)

Actual status of QPA of **pharmaceuticals**?

Why quantifying on an **absolute** scale?



Tailoring methodology to characteristics of pharmaceuticals

Choice of quantification method

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Tailoring methodology to characteristics of pharmaceuticals

Choice of quantification method

N. V. Y. Scarlett & I. C. Madsen, Powder Diffraction, **21**, 4, 278-284 (2006). PONKCS method



Actual status of QPA of **pharmaceuticals**?

Why quantifying on an **absolute** scale?

(relative scale: invisible amorphous/unknown, ex: interconversion to amorphous)





Tailoring methodology to characteristics of pharmaceuticals

Choice of quantification method

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boratory XRPD

Synchrotron XRPD

1.85

1.9

1.8

Pushing instrument limits

Synchrotron radiation + Position sensitive detector + capillary geometry

LoQ<0.05 wt%, LoD<0.01 wt% High angular (FWHM) resolution Data collection efficiency Data modelling No transparency effect Tunable wavelength













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CHALLENGES

Tailoring methodology

Know your sample: organics Light molecules, poor scattering power, large unit cells, low symmetry, peak overlapping, radiation sensitive, low absorption...

Spatial inhomogeneities ⇒ sample more powder volumes

Semi-crystalline materials Degree of Crystallinity (DoC)

Correlation amorphous contributions sample vs container



CHALLENGES

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Choice of quantification method	Direct corrComparabUnknown
Internal standard method	• Amorphou • Universal
Calibration curve: Y/N	Internal stTime constPowder sa
	Analyte m

- rection for instrumental effects
- le matrix effects
- compounds
- s quantification, Absolute scale
- tandard tailored to analyte
- suming powder processing
- amples only
- ixture contamination

Which internal standard?





Crystanie alameter (µm)	40	10	1
Crystallites (20 mm ³)	5.97×10^{5}	3.82×10^{7}	3.82×10^{10}
Number diffracting	12	760	38 000
$\sigma_{\rm PS}$	0.289	0.036	0.005

C Madsen and N. V. Y. Scarlett in Powder Diffraction: Theory and Practice, 2008 Robert E. Dinnebier and Simon J. L. Billinge, Print ISBN: 978-0-85404-231-9, DOI:10.1039/978184755823 Deane K. Smith Powder Diffraction, 16, pp 186-191, (2001), doi:10.1154/1.1423285

Compromises ...

Alumina

CHALLENGES

Nice peak shape Known DoC (NIST standard SRM676 series)



Density ca. 3.9 g.cm⁻³ LAC (12.4 keV) = 37.3 cm⁻¹ Small wt% ⇔ weighting errors

Compromises ...

Alumina

Nice peak shape Known DoC (NIST standard SRM676 series)

						2 He	
	5 B	6 C	7 N	8 0	9 F	10 Ne	
5	13 Al	14 Si	15 P	16 S	17 Cl	18 Ar	
30 Zn	31 Ga	32 Ge	33 As	34 Se	35 Br	36 Kr	

Density ca. 3.9 g.cm⁻³ LAC (12.4 keV) = 37.3 cm⁻¹ Small wt% ⇔ weighting errors

Beyond Alumina

Diamond

LAC (12.4 keV) = 3.2 cm⁻¹

hBN

Density ca. 2.1 g.cm⁻³ LAC (12.4 keV) = 2.9 cm⁻¹

Helps to homogenize blends



Flakes ⇒ difficult peak shape Standard Rietveld refinement won't work **Alternative** analysis strategy

Density ca. 3.5 g.cm⁻³ Small wt% ⇔ weighting errors

Very few peaks <60° 2θ ⇒ limited redundancy for peak overlap

<u>Purity</u> of grinding media





High order polynomial:



Main separate contributions (physically-based background):



- REAL samples: Amorphous pattern not always available
- (i.e. calibration curve amorphous/crystalline not an option)

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Ø

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Excelsus Assessing the DoC – 'Testimonial' example of Alumina





Background fits nicely with identified diffuse contributions

Expected DoC between 99 and 100 wt%: we are NOT sensitive to <1 wt% amorphous content

Excelsus Assessing the DoC – Consistency with *ad-hoc* mixtures

Test method against *ad-hoc* physical mixtures of amorphous /crystalline lactose



Ad-hoc mixtures of lactose: relative error between weighted and refined ratio in the range 0.5 – 16 %

Excelsus Assessing the DoC – for all pure phases



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Excelsus (Overview calibration curve mixtures

- Sucrose/Alumina-hBN-Diamond mixtures
- Small wt% to improve distribution homogeneity and adapted to scattering power



Excelsus A Overview calibration curve mixtures

Comparison calibration curves internal standard/sucrose



Excelsus Diamond as internal standard – calibration curve

Strongly correlated Diamond/Sucrose reflections





Limits of the least square optimization



The three candidates can be used under favorable circumstances: Alumina: restrained wt% Diamond: if peak overlapping allows hBN: if peak overlapping allows and intensity (not more than 20wt%)

- Validate DoC method
- Try DoC using the scaled amorphous phase
- Assess the lower limit of amorphous-QPA

- Ternary mixtures with each of the standards (increased Diamond wt%)
- Test of alternative analysis methods (PONKCS, 'Siroquant'-like, proper model of hBN distortions, 'Principal Component Analysis'-like)

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Useful references

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Thank you for your attention Questions?

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